

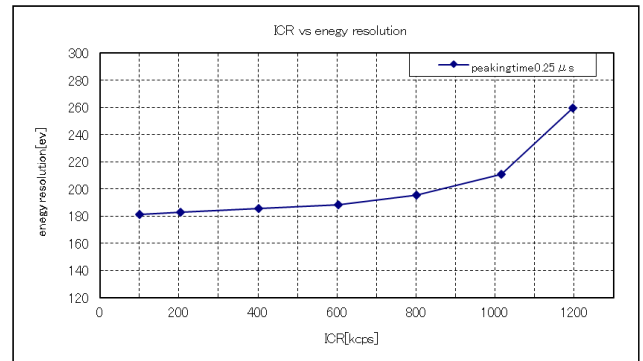
XSDD50 Series is all-in-one system which has detector, which is needed X-ray absorption microstructure measurement in the analysis of materials field, data acquisition board, and power supply. It was realized high-sensitivity by multiple SDD detector with high-count rate and energy resolution. Additionally, it is possible to be measured high-count rate by a transistor reset processing and DSP processing.

XSDD50-07

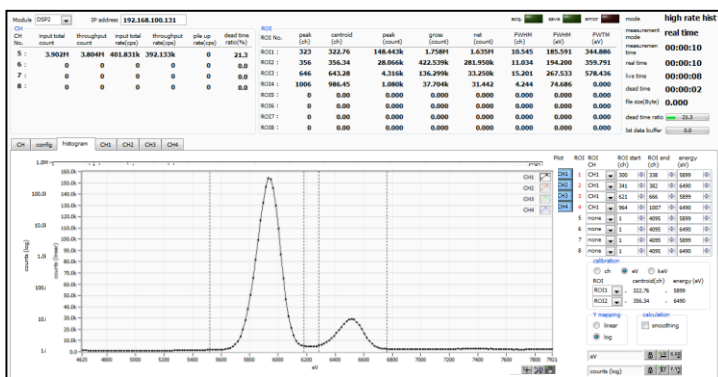


Left: 100MADC, Right: SDD for power supply

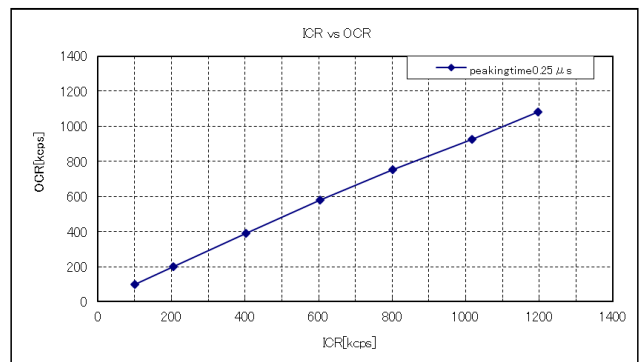
- All element area : 455mm² (65mm² × 7 element)
- All effective area : 350mm²
(collimated to 50mm² × 7 element)
- Function : Histogram, List, Waveform, ROI-SCA
- ADC : 8CH 100MSPS 14bit
- Energy resolution : 244eV@5.9keV MnKα
(Peakingtime 0.25ms, 1000kOCR)
- Power supply for SDD : -200V, ±5V, +3.3V
- Interface : Ethernet (TCP/IP)
- Accessory : Application, Instruction manual



ICR vs Energy resolution



400k ICR 185eV@5.9keV 0.25ms Peaking Time Application



ICR vs OCR

*Please note that contents may change without prior notice.